Aleksander Jablonski

List of Publications by Year
in descending order

240 papers	7,550 citations	61984 43 h-index	71685 76 g-index
245 all docs	245 docs citations	245 times ranked	4456 citing authors

#	Article	IF	Citations
1	Analytical formalism for calculations of parameters needed for quantitative analysis by X-ray photoelectron spectroscopy. Computer Physics Communications, 2022, 272, 108233.	7.5	1
2	Multiple elastic scattering of electrons in condensed matter (new version announcement). Computer Physics Communications, 2022, 278, 108402.	7.5	1
3	elsepaâ€"Dirac partial-wave calculation of elastic scattering of electrons and positrons by atoms, positive ions and molecules (New Version Announcement). Computer Physics Communications, 2021, 261, 107704.	7.5	15
4	Universal analytical formula for the emission depth distribution function for photoelectrons with kinetic energies up to 5000 eV. Surface Science, 2021, 706, 121778.	1.9	1
5	Effective Attenuation Lengths for Different Quantitative Applications of X-ray Photoelectron Spectroscopy. Journal of Physical and Chemical Reference Data, 2020, 49, .	4.2	30
6	Surface Characterization of MoS2 Atomic Layers Mechanically Exfoliated on a Si Substrate. Materials, 2020, 13, 3595.	2.9	5
7	Improved algorithm for calculating high accuracy values of the Chandrasekhar function. Computer Physics Communications, 2020, 251, 107237.	7.5	3
8	The Chandrasekhar function for modeling photoelectron transport in solids. Computer Physics Communications, 2019, 235, 489-501.	7.5	6
9	Evaluation of procedures for overlayer thickness determination from XPS intensities. Surface Science, 2019, 688, 14-24.	1.9	17
10	A note on calculations of photoelectron partial intensities for energies reaching 4000 eV. Journal of Electron Spectroscopy and Related Phenomena, 2019, 234, 34-46.	1.7	1
11	Effective attenuation length dependence on photoelectron kinetic energy for gold from 1 keV to 10 keV: Role of island growth in overlayer experiments. Journal of Electron Spectroscopy and Related Phenomena, 2019, 236, 27-32.	1.7	5
12	Elastic scattering effects in quantitative AES and XPS: Case studies. Journal of Surface Analysis (Online), 2019, 26, 104-105.	0.1	0
13	Surface characterization of low-temperature grown yttrium oxide. Applied Surface Science, 2018, 437, 347-356.	6.1	10
14	Modeling and parameterization of photoelectrons emitted in condensed matter by linearly polarized synchrotron radiation. Surface Science, 2018, 667, 121-137.	1.9	13
15	Effective attenuation lengths for quantitative determination of surface composition by Auger-electron spectroscopy and X-ray photoelectron spectroscopy. Journal of Electron Spectroscopy and Related Phenomena, 2017, 218, 1-12.	1.7	22
16	Multiple elastic scattering of electrons in condensed matter. Computer Physics Communications, 2017, 210, 92-102.	7.5	5
17	Modeling of Electron Transport in the Surface Region of Solids: Metrology of Quantitative Analysis by Electron Spectroscopies. Journal of Surface Analysis (Online), 2017, 24, 115-122.	0.1	0
18	Surface sensitivity of elastic peak electron spectroscopy. Applied Surface Science, 2016, 378, 87-101.	6.1	6

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19	The chemical states of As 3d in highly doped ZnO grown by Molecular Beam Epitaxy and annealed in different atmospheres. Thin Solid Films, 2016, 605, 283-288.	1.8	9
20	Arsenic chemical state in MBE grown epitaxial ZnO layers â€“ doped with As, N and Sb. Journal of Alloys and Compounds, 2016, 687, 937-942.	5.5	11
21	Surface studies of praseodymium by electron spectroscopies. Applied Surface Science, 2016, 388, 691-695.	6.1	2
22	Surface characterization of graphene based materials. Applied Surface Science, 2016, 388, 696-703.	6.1	7
23	Analytical theory of elastic electron backscattering from elements, alloys and compounds: Comparison with experimental data. Journal of Electron Spectroscopy and Related Phenomena, 2016, 206, 24-45.	1.7	10
24	The Chandrasekhar function revisited. Computer Physics Communications, 2015, 196, 416-428.	7.5	10
25	Photoelectron transport in the surface region of solids: universal analytical formalism for quantitative applications of electron spectroscopies. Journal Physics D: Applied Physics, 2015, 48, 075301.	2.8	20
26	Effective attenuation lengths for photoelectrons emitted by high-energy laboratory X-ray sources. Journal of Electron Spectroscopy and Related Phenomena, 2015, 199, 27-37.	1.7	33
27	Electron inelastic mean free paths in cerium dioxide. Applied Surface Science, 2015, 341, 196-202.	6.1	23
28	Charge injection in metal/organic/metal structures with ZnO:Al/organic interface modified by Zn1â^'xMgxO:Al layer. Organic Electronics, 2015, 25, 135-142.	2.6	7
29	Parameterization of HAXPES photoelectrons with kinetic energies up to 10keV. Applied Surface Science, 2015, 346, 503-519.	6.1	8
30	Atomic layer deposition of Zn1â^'x Mg x O:Al transparent conducting films. Journal of Materials Science, 2014, 49, 1512-1518.	3.7	12
31	Cross Sections for Inner-Shell Ionization by Electron Impact. Journal of Physical and Chemical Reference Data, 2014, 43, .	4.2	133
32	Contribution of elastic photoelectron scattering to the shape of the measured XPS intensity inâ€¢depth profile. Surface and Interface Analysis, 2014, 46, 269-275.	1.8	0
33	Elastic-peak electron spectroscopy (EPES) studies of ZnO single crystals. Journal of Alloys and Compounds, 2014, 590, 553-556.	5.5	7
34	Angular distribution of elastic electron backscattering from surfaces: determination of the electron inelastic mean free path. Journal Physics D: Applied Physics, 2014, 47, 055301.	2.8	12
35	XPS method as a useful tool for studies of quantum well epitaxial materials: Chemical composition and thermal stability of InGaN/GaN multilayers. Journal of Alloys and Compounds, 2014, 597, 181-187.	5.5	5
36	Emission depth distribution function for photoelectrons emitted by laboratory hard X-ray radiation sources. Journal of Electron Spectroscopy and Related Phenomena, 2014, 195, 26-42.	1.7	14

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37	XPS study of arsenic doped ZnO grown by Atomic Layer Deposition. Journal of Alloys and Compounds, 2014, 582, 594-597.	5.5	25
38	Homogeneous and heterogeneous magnetism in (Zn,Co)O: From a random antiferromagnet to a dipolar superferromagnet by changing the growth temperature. Physical Review B, 2013, 88, .	3.2	43
39	Angular distribution of photoelectrons emitted by the laboratory soft and hard X-ray radiation sources. Journal of Electron Spectroscopy and Related Phenomena, 2013, 189, 81-95.	1.7	17
40	Studies of the hot-pressed TiN material by electron spectroscopies. Journal of Alloys and Compounds, 2013, 546, 280-285.	5.5	14
41	Simulation of the backscattered electron intensity of multi layer structure for the explanation of secondary electron contrast. Ultramicroscopy, 2013, 124, 88-95.	1.9	2
42	Improved algorithm for calculating the Chandrasekhar function. Computer Physics Communications, 2013, 184, 440-442.	7.5	6
43	Elastic photoelectron scattering effects in the XPS analysis of stratified samples. Journal Physics D: Applied Physics, 2012, 45, 315302.	2.8	13
44	Elastic photoelectron-scattering effects in quantitative X-ray photoelectron spectroscopy. Surface Science, 2012, 606, 644-651.	1.9	15
45	Photoelectron emission from thin overlayers. Journal of Electron Spectroscopy and Related Phenomena, 2012, 185, 498-508.	1.7	4
46	ALD grown zinc oxide with controllable electrical properties. Semiconductor Science and Technology, 2012, 27, 074011.	2.0	134
47	An effective algorithm for calculating the Chandrasekhar function. Computer Physics Communications, 2012, 183, 1773-1782.	7.5	15
48	Experimental verification of the shape of the excitation depth distribution function for AES. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2011, 29, 051401.	2.1	1
49	Surface and in-depth characterization of InGaN compounds synthesized by plasma-assisted molecular beam epitaxy. Journal of Alloys and Compounds, 2011, 509, 9565-9571.	5.5	14
50	Surface Sensitivity of Auger-Electron Spectroscopy and X-ray Photoelectron Spectroscopy. Journal of Surface Analysis (Online), 2011, 17, 170-176.	0.1	19
51	Experimental determination of the electron elastic backscattering probability and the surface excitation parameter for Si, Ni, Cu and Ag at 0.5 and 1 keV energies. Surface and Interface Analysis, 2011, 43, 1365-1370.	1.8	3
52	The Backscattering Correction Factor in AES: A New Outlook. Journal of Surface Analysis (Online), 2011, 17, 213-219.	0.1	3
53	Determination of Surface Composition by X-ray Photoelectron Spectroscopy Taking into Account Elastic Photoelectron Collisions. Analytical Sciences, 2010, 26, 155-164.	1.6	16
54	Remarks on Some Reference Materials for Applications in Elastic Peak Electron Spectroscopy. Analytical Sciences, 2010, 26, 239-246.	1.6	9

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55	Improved analytical formulae for correcting elastic-scattering effects in X-ray photoelectron spectroscopy. Surface Science, 2010, 604, 327-336.	1.9	16
56	Dependence of the AES backscattering correction factor on the experimental configuration. Surface Science, 2010, 604, 1928-1939.	1.9	7
57	Progress in quantitative surface analysis by X-ray photoelectron spectroscopy: Current status and perspectives. Journal of Electron Spectroscopy and Related Phenomena, 2010, 178-179, 331-346.	1.7	184
58	Calculations of Auger intensity versus beam position for a sample with layers perpendicular to its surface. Journal Physics D: Applied Physics, 2010, 43, 275301.	2.8	0
59	Quantification of surface-sensitive electron spectroscopies. Surface Science, 2009, 603, 1342-1352.	1.9	19
60	Overlayer thickness determination by XPS using the multiline approach. Surface and Interface Analysis, 2009, 41, 193-204.	1.8	47
61	Surface sensitivity of X-ray photoelectron spectroscopy. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 2009, 601, 54-65.	1.6	178
62	The backscattering factor for systems with a non-uniform surface region: Definition and calculations. Surface Science, 2009, 603, 2047-2056.	1.9	6
63	The inelastic mean free path of electrons. Past and present research. Vacuum, 2009, 84, 134-136.	3.5	6
64	Determination of electron inelastic mean free paths for poly[methyl(phenyl)silylene] films. Polymer, 2009, 50, 2445-2450.	3.8	3
65	The effect of inelastic absorption on the elastic scattering of electrons and positrons in amorphous solids. Journal of Electron Spectroscopy and Related Phenomena, 2009, 175, 41-54.	1.7	20
66	Cross sections for ionization of K, L and M shells of atoms by impact of electrons and positrons with energies up to 1GeV: Analytical formulas. Atomic Data and Nuclear Data Tables, 2009, 95, 871-909.	2.4	98
67	Backscattering yield paradox for samples with perpendicular layers. Journal Physics D: Applied Physics, 2009, 42, 195301.	2.8	1
68	Practical expressions for the mean escape depth, the information depth, and the effective attenuation length in Auger-electron spectroscopy and x-ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2009, 27, 253-261.	2.1	96
69	Practical formulas for inner-shell ionization cross sections by electron impact: Applications in quantitative Auger electron spectroscopy. Journal of Applied Physics, 2009, 106, 053706.	2.5	4
70	The Backscattering Factor for Systems with Non-uniform In-depth Profile. Journal of Surface Analysis (Online), 2009, 15, 259-263.	0.1	0
71	Modified predictive formula for the electron stopping power. Journal of Applied Physics, 2008, 103, .	2.5	24
72	The Inelastic Mean Free Path Î¿f Electrons. Research in Budapest, Warsaw, WrocÅ‚aw and Clermont-Ferrand. Brief History and New Results. Acta Physica Polonica A, 2008, 114, S-49-S-58.	0.5	2

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73	Effects of Electron Backscattering in Auger Electron Spectroscopy: Recent Developments. Journal of Surface Analysis (Online), 2008, 15, 139-149.	0.1	0
74	Improved algorithm for calculating transport cross sections of electrons with energies from<mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" display="inline"><mml:mrow><mml:mn>50</mml:mn><mml:mspace width="0.3em" /><mml:mi>eV</mml:mi><mml:mspace width="0.3em" /><mml:mtext>to</mml:mtext><mml:mspace width="0.3em" /><mml:mn>30</mml:mn><mml:mspace width="0.3em" /><mml:mi>keV</mml:mi></mml:mrow></mml:math>. Physical Review B, 2007, 76, .	3.2	30
75	Angle-resolved elastic peak electron spectroscopy: Role of surface excitations. Surface Science, 2007, 601, 3409-3420.	1.9	20
76	Attenuation of photoelectrons and Auger electrons leaving nickel deposited on a gold surface. Surface and Interface Analysis, 2007, 39, 916-921.	1.8	6
77	Evaluation of the inelastic mean free path (IMFP) of electrons in polyaniline and polyacetylene samples obtained from elastic peak electron spectroscopy (EPES). Open Physics, 2007, 5, .	1.7	5
78	Angular-resolved elastic peak electron spectroscopy: experiment and Monte Carlo calculations. Surface and Interface Analysis, 2006, 38, 615-619.	1.8	15
79	New universal expression for the electron stopping power for energies between 200 eV and 30 keV. Surface and Interface Analysis, 2006, 38, 76-83.	1.8	39
80	Measured electron IMFPs for SiC. Surface and Interface Analysis, 2006, 38, 644-647.	1.8	19
81	Experimental determination of the inelastic mean free path (IMFP) of electrons in selected oxide films applying surface excitation correction. Surface and Interface Analysis, 2006, 38, 624-627.	1.8	16
82	Dependence of calculated electron effective attenuation lengths on transport mean free paths obtained from two atomic potentials. Surface and Interface Analysis, 2006, 38, 1348-1356.	1.8	10
83	EPES sampling depth paradox for overlayer/substrate system. Journal of Electron Spectroscopy and Related Phenomena, 2006, 150, 56-61.	1.7	11
84	Angle-resolved elastic-peak electron spectroscopy: Solid-state effects. Surface Science, 2006, 600, 4464-4474.	1.9	9
85	Inelastic Mean Free Path Data for Si Corrected for Surface Excitation. Microscopy and Microanalysis, 2005, 11, 581-585.	0.4	0
86	The backscattering factor for the Au N67VV Auger transition. Applied Surface Science, 2005, 252, 905-915.	6.1	6
87	Modeling of elastic and inelastic electron backscattering from surfaces. Progress in Surface Science, 2005, 79, 3-27.	8.3	15
88	The backscattering factor in Auger-electron spectroscopy: New approach for an old subject. Surface Science, 2005, 574, 219-232.	1.9	28
89	Role of the emission depth distribution function in quantification of electron spectroscopies. Surface Science, 2005, 586, 115-128.	1.9	31
90	Determination of the electron inelastic mean free path for samarium. Surface Science, 2005, 595, 1-5.	1.9	3

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91	elsepaâ€"Dirac partial-wave calculation of elastic scattering of electrons and positrons by atoms, positive ions and molecules. Computer Physics Communications, 2005, 165, 157-190.	7.5	507
92	Characterization of thin films on the nanometer scale by Auger electron spectroscopy and X-ray photoelectron spectroscopy. Applied Surface Science, 2005, 239, 470-480.	6.1	38
93	Studies of iron and iron oxide layers by electron spectroscopes. Applied Surface Science, 2005, 252, 330-338.	6.1	10
94	Experimental and model study of the Rh/Al system by means of EPES. Surface and Interface Analysis, 2005, 37, 998-1005.	1.8	3
95	NIST databases with electron elastic-scattering cross sections, inelastic mean free paths, and effective attenuation lengths. Surface and Interface Analysis, 2005, 37, 1068-1071.	1.8	44
96	Monte Carlo strategies for simulations of electron backscattering from surfaces. Surface and Interface Analysis, 2005, 37, 861-874.	1.8	39
97	Determination of the electron inelastic mean free path in solids from the elastic electron backscattering intensity. Surface and Interface Analysis, 2005, 37, 1035-1044.	1.8	32
98	Evaluation of elastic-scattering cross sections for electrons and positrons over a wide energy range. Surface and Interface Analysis, 2005, 37, 1115-1123.	1.8	14
99	Inelastic mean-free path of electrons at nanocrystalline diamond surfaces. Applied Physics Letters, 2005, 87, 262114.	3.3	22
100	Elastic electron backscattering from silicon surfaces: effect of charge-carrier concentration. Surface and Interface Analysis, 2004, 36, 809-811.	1.8	1
101	Surface excitation of selected conducting polymers studied by elastic peak electron spectroscopy(EPES) and reflection electron energy loss spectroscopy(REELS). Surface and Interface Analysis, 2004, 36, 1056-1059.	1.8	4
102	Information depth for elastic-peak electron spectroscopy. Surface Science, 2004, 551, 106-124.	1.9	59
103	Surface excitations in electron backscattering from silicon surfaces. Surface Science, 2004, 562, 92-100.	1.9	31
104	Hydrogen and surface excitation in electron spectra of polyethylene. Surface Science, 2004, 566-568, 544-548.	1.9	33
105	IMFP measurements near Auâ€"Ni alloy surfaces by EPES: indirect evidence of submonolayer Au surface enrichment. Surface Science, 2004, 566-568, 856-861.	1.9	9
106	Energy dependence of electron inelastic mean free paths in bulk GaN crystals. Surface Science, 2004, 566-568, 1234-1239.	1.9	21
107	Differential cross sections for elastic scattering of electrons by atoms and solids. Journal of Electron Spectroscopy and Related Phenomena, 2004, 137-140, 299-303.	1.7	12
108	Elastic electron backscattering from surfaces in selected angular ranges. Applied Surface Science, 2004, 229, 67-80.	6.1	1

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109	Determination of the electron inelastic mean free path in some binary alloys for application in quantitative surface analysis. Applied Surface Science, 2004, 235, 15-20.	6.1	7
110	Comparison of Electron Elastic-Scattering Cross Sections Calculated from Two Commonly Used Atomic Potentials. Journal of Physical and Chemical Reference Data, 2004, 33, 409-451.	4.2	204
111	Electron effective attenuation lengths in electron spectroscopies. Journal of Alloys and Compounds, 2004, 362, 26-32.	5.5	25
112	Analytical applications of elastic electron backscattering from surfaces. Progress in Surface Science, 2003, 74, 357-374.	8.3	35
113	Surface excitation effects in elastic peak electron spectroscopy. Surface Science, 2003, 531, L335-L339.	1.9	24
114	Information depth and the mean escape depth in Auger electron spectroscopy and x-ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2003, 21, 274-283.	2.1	74
115	Remarks on the definition of the backscattering factor in AES. Surface Science, 2002, 499, 219-228.	1.9	33
116	The NIST Electron Effective-Attenuation-Length Database. Journal of Surface Analysis (Online), 2002, 9, 322-325.	0.1	50
117	The electron attenuation length revisited. Surface Science Reports, 2002, 47, 33-91.	7.2	215
118	Determination of inelastic mean free paths for AuPd alloys by elastic peak electron spectroscopy (EPES). Surface and Interface Analysis, 2002, 33, 23-28.	1.8	14
119	Electron effective attenuation lengths for applications in Auger electron spectroscopy and x-ray photoelectron spectroscopy. Surface and Interface Analysis, 2002, 33, 211-229.	1.8	101
120	Influence of surface composition and density on electron inelastic mean free paths in Ge. Surface and Interface Analysis, 2002, 33, 381-393.	1.8	4
121	Elastic electron backscattering from silicon surfaces: effect of surface roughness. Surface and Interface Analysis, 2002, 34, 215-219.	1.8	15
122	Surface studies and catalytic properties of the bifunctional bulk MoO2 system. Surface and Interface Analysis, 2002, 34, 225-229.	1.8	38
123	Comparisons of practical attenuation lengths obtained from different algorithms for application in XPS. Surface Science, 2002, 520, 78-96.	1.9	31
124	Escape probability of photoelectrons from silver sulphide. Surface Science, 2001, 473, 8-16.	1.9	27
125	Measurement of silicon dioxide film thicknesses by X-ray photoelectron spectroscopy. AIP Conference Proceedings, 2001, , .	0.4	2
126	NIST data resources for surface analysis by X-ray photoelectron spectroscopy and Auger electron spectroscopy. Journal of Electron Spectroscopy and Related Phenomena, 2001, 114-116, 1097-1102.	1.7	41

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127	Effects of elastic-electron scattering on measurements of silicon dioxide film thicknesses by X-ray photoelectron spectroscopy. Journal of Electron Spectroscopy and Related Phenomena, 2001, 114-116, 1139-1143.	1.7	41
128	Electron inelastic mean free paths (IMFPs) in binary Au-Cu alloys determined by elastic peak electron spectroscopy. Surface and Interface Analysis, 2001, 31, 415-420.	1.8	5
129	Elastic electron backscattering from overlayer/substrate systems. Surface and Interface Analysis, 2001, 31, 825-834.	1.8	19
130	Intercomparison of methods for separation of REELS elastic peak intensities for determination of IMFP. Surface and Interface Analysis, 2001, 31, 1-10.	1.8	14
131	Influence of elastic-electron scattering on measurements of silicon dioxide film thicknesses by x-ray photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2001, 19, 2604-2611.	2.1	34
132	EMISSION DEPTH DISTRIBUTION FUNCTION OF Al 2s PHOTOELECTRONS IN Al2O3. Surface Review and Letters, 2000, 07, 109-114.	1.1	7
133	Evaluation of electron inelastic mean free paths for selected elements and compounds. Surface and Interface Analysis, 2000, 29, 108-114.	1.8	62
134	Experimental determination of the inelastic mean free path of electrons in GaP and InAs. Surface and Interface Analysis, 2000, 30, 195-198.	1.8	17
135	Inelastic mean free path measurements of electrons near nickel surfaces. Surface and Interface Analysis, 2000, 30, 217-221.	1.8	9
136	Measurements of the escape probability of photoelectrons and the inelastic mean free path in silver sulphide. Surface and Interface Analysis, 2000, 30, 222-227.	1.8	5
137	Determination of the IMFP from electron elastic backscattering probability. Surface and Interface Analysis, 2000, 29, 582-595.	1.8	14
138	Determination of the inelastic mean free path of electrons in polyaniline samples by elastic peak electron spectroscopy. Surface and Interface Analysis, 2000, 29, 614-623.	1.8	9
139	Evaluation of theoretical models for elastic electron backscattering from surfaces. Progress in Surface Science, 2000, 63, 135-175.	8.3	66
140	Catalytic reactivity and surface chemistry of polyaniline(EB)â€“Pdâ€“H2O systems. Topics in Catalysis, 2000, 11/12, 307-316.	2.8	5
141	Effects of interaction potential on elastic-electron-scattering parameters in surface-sensitive electron spectroscopies. Surface Science, 2000, 463, 29-54.	1.9	17
142	Determination of the Inelastic Mean Free Path of Electrons in Different Polyaniline Samples. Langmuir, 2000, 16, 1415-1423.	3.5	43
143	Evaluation of electron inelastic mean free paths for selected elements and compoundsâ€. , 2000, 29, 108.		1
144	Experimental determination of the inelastic mean free path of electrons in GaP and InAs. , 2000, 30, 195.		1

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145	Consistency of calculated and measured electron inelastic mean free paths. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1999, 17, 1122-1126.	2.1	19
146	Relationships between electron inelastic mean free paths, effective attenuation lengths, and mean escape depths. Journal of Electron Spectroscopy and Related Phenomena, 1999, 100, 137-160.	1.7	136
147	Determination of the electron inelastic mean free path in polyacetylene by elastic peak electron spectroscopy using different spectrometers. Applied Surface Science, 1999, 144-145, 168-172.	6.1	12
148	Experimental determination of the inelastic mean free path of electrons in GaSb and InSb. Applied Surface Science, 1999, 144-145, 173-177.	6.1	8
149	Evaluation of Calculated and Measured Electron Inelastic Mean Free Paths Near Solid Surfaces. Journal of Physical and Chemical Reference Data, 1999, 28, 19-62.	4.2	465
150	Escape probability of electrons from solids. Influence of elastic electron scattering. Surface Science, 1999, 432, 211-227.	1.9	47
151	Practical correction formula for elastic electron scattering effects in attenuation of auger electrons and photoelectrons. Surface and Interface Analysis, 1998, 26, 17-29.	1.8	41
152	Escape probability of s-photoelectrons leaving aluminium and copper oxides. Surface and Interface Analysis, 1998, 26, 182-187.	1.8	24
153	Evaluation of validity of the depth-dependent correction formula (CF) for elastic electron scattering effects in AES and XPS. Surface and Interface Analysis, 1998, 26, 374-384.	1.8	32
154	Determination of the inelastic mean free paths of electrons in copper and copper oxides by elastic peak electron spectroscopy (EPES). Surface and Interface Analysis, 1998, 26, 400-411.	1.8	27
155	The inelastic mean free path and the inelastic scattering cross-section of electrons in GaAs determined from highly resolved electron energy spectra. Surface Science, 1998, 402-404, 491-495.	1.9	12
156	Dependence of experimentally determined inelastic mean free paths of electrons on the measurement geometry. Surface Science, 1998, 412-413, 42-54.	1.9	55
157	Transport cross section for electrons at energies of surface-sensitive spectroscopies. Physical Review B, 1998, 58, 16470-16480.	3.2	45
158	Determination of the inelastic mean free paths of electrons in copper and copper oxides by elastic peak electron spectroscopy (EPES). , 1998, 26, 400.		1
159	Evaluation of correction parameters for elastic-scattering effects in x-ray photoelectron spectroscopy and Auger electron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1997, 15, 2095-2106.	2.1	47
160	Experimental and theoretical tests of elastic scattering effects in XPS. Surface Science, 1997, 387, 288-299.	1.9	18
161	Escape probability of O1s photoelectrons leaving copper oxide. Journal of Electron Spectroscopy and Related Phenomena, 1997, 85, 257-262.	1.7	20
162	Escape probability of signal photoelectrons from non-crystalline solids: influence of anisotropy of photoemission. Journal of Electron Spectroscopy and Related Phenomena, 1997, 87, 127-140.	1.7	71

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163	Emission-depth Dependence of the Signal Photoelectron Energy Spectrum. Surface and Interface Analysis, 1997, 25, 119-131.	1.8	10
164	Surface Composition of the CoPd Alloys Studied by Electron Spectroscopies. Surface and Interface Analysis, 1997, 25, 356-365.	1.8	22
165	Quantitative XPS: Influence of Elastic Electron Scattering in Quantification by Peak Shape Analysis. Surface and Interface Analysis, 1997, 25, 404-408.	1.8	19
166	The Excitation Depth Distribution Function for Auger Electrons Created by Electron Impact. Surface and Interface Analysis, 1997, 25, 688-698.	1.8	16
167	Maximum probability of elastic electron backscattering from surfaces of amorphous and polycrystalline solids. Surface Science, 1996, 347, 207-214.	1.9	14
168	Universal quantification of elastic scattering effects in AES and XPS. Surface Science, 1996, 364, 380-395.	1.9	49
169	Mean escape depth of signal photoelectrons from amorphous and polycrystalline solids. Physical Review B, 1996, 54, 10927-10937.	3.2	64
170	Elastic Electron Backscattering from Surfaces at Low Energies. Surface and Interface Analysis, 1996, 24, 781-785.	1.8	21
171	The influence of elastic scattering on the concentration dependence of the photoelectron line intensity. Applied Surface Science, 1996, 100-101, 20-24.	6.1	3
172	Database of correction parameters for the elastic scattering effects in XPS. Surface and Interface Analysis, 1995, 23, 29-37.	1.8	68
173	Test of elastic electron scattering corrections for quantitative XPS. Surface and Interface Analysis, 1995, 23, 559-564.	1.8	4
174	Efficient calculation of photoelectron angular distribution. Surface and Interface Analysis, 1995, 23, 823-832.	1.8	11
175	Towards a universal description of elastic scattering effects in X-ray photoelectron spectroscopy. Journal of Electron Spectroscopy and Related Phenomena, 1995, 74, 207-229.	1.7	63
176	Photoelectron escape depth. Journal of Electron Spectroscopy and Related Phenomena, 1995, 76, 443-447.	1.7	35
177	Differential elastic scattering and backscattering cross sections of H, Si and O in the low energy (2â€“50 eV) range for electron spectroscopy on porous Si. Vacuum, 1995, 46, 587-589.	3.5	1
178	Experimental determination of the inelastic mean free path for Cu, Ag, W, Au and Ta, in the energy range 500â€“3000 eV by elastic peak electron spectroscopy and using Ni reference sample. Vacuum, 1995, 46, 591-594.	3.5	27
179	A theory of quantitative angle-resolved X-ray photoelectron spectroscopy. Vacuum, 1995, 46, 613-616.	3.5	7
180	Experimental determination of the inelastic mean free path (IMFP) of electrons in Cr, Mo, Ge and Si based on the elastic peak intensity ratio with a Ni reference sample. Surface Science, 1995, 331-333, 1203-1207.	1.9	29

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181	Path-length distribution of photoelectrons emitted from homogeneous noncrystalline solids: Consequences for inelastic-background analysis. Physical Review B, 1995, 52, 5935-5946.	3.2	30
182	Quantitative analysis by XPS using the multiline approach. Surface and Interface Analysis, 1994, 21, 724-730.	1.8	41
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